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Application/Control No.	Applicant(s)/Pat Reexamination
09/766,407	TANNER ET A

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Examiner

Blaine Basom

Applicant(s)/Patent under Reexamination

TANNER ET AL.

Art Unit

SEARCHED				
Class	Subclass	Date	Examiner	
UPDATED	SEARCH	12/4/2007	втв	
715	745, 747	12/4/2007	втв	
715	749, 734	12/4/2007	втв	
715	735, 748	12/4/2007	ВТВ	
715	744	12/4/2007	втв	
709	220	12/5/2007	втв	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
715	735	12/7/2007	втв	
717	175, 177	12/7/2007	втв	
	EARCH (see h notes)	12/7/2007	втв	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST SEARCH (see search notes)	12/7/2007	втв		
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